Welcome to Galaxy Examinator reports

Date: Wed Sep 4 15:52:06 2024
Product :
LotID :

Table of contents

Tests Statistics

Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
0	func_T1	F	n/a .	n/a .	Samples	50	0	n/a .	n/a .	n/a .	n/a .	100.00 %
1	func_T2	F	n/a .	n/a .	Samples	50	0	n/a .	n/a .	n/a .	n/a .	100.00 %
2	func_T3	F	n/a .	n/a .	Samples	50	0	n/a .	n/a .	n/a .	n/a .	100.00 %
3	Continuity_PPMU1 cs 19.g106	P	−1200 mV	−100 mV	Samples	50	0	−639.204 mV	0.59363 mV	308.8	302.8	100.00 %
4	Continuity_PPMU1 p20 19.g128	P	−1200 mV	−100 mV	Samples	50	0	−640.382 mV	0.96489 mV	190.0	186.7	100.00 %
5	Continuity_PPMU1 p21 19.g126	P	−1200 mV	−100 mV	Samples	50	0	−640.401 mV	0.899843 mV	203.7	200.2	100.00 %
6	Continuity_PPMU1 p22 19.e126	P	−1200 mV	−100 mV	Samples	50	0	−640.346 mV	0.835683 mV	219.4	215.5	100.00 %
7	Continuity_PPMU1 p23 19.e124	P	−1200 mV	−100 mV	Samples	50	0	−640.312 mV	0.820142 mV	223.5	219.6	100.00 %
8	Continuity_PPMU1 p40 19.e130	P	−1200 mV	−100 mV	Samples	50	0	−641.037 mV	0.995041 mV	184.2	181.2	100.00 %
9	Continuity_PPMU1 p41 19.e139	P	−1200 mV	−100 mV	Samples	50	0	−641.138 mV	1.06819 mV	171.6	168.9	100.00 %
10	Continuity_PPMU1 p42 19.e147	P	−1200 mV	−100 mV	Samples	50	0	−641.359 mV	0.884027 mV	207.4	204.1	100.00 %
11	Continuity_PPMU1 p43 19.e151	P	−1200 mV	−100 mV	Samples	50	0	−641.045 mV	0.90153 mV	203.4	200.0	100.00 %
12	Continuity_PPMU1 p50 19.e128	P	−1200 mV	−100 mV	Samples	50	0	−640.299 mV	1.02957 mV	178.1	174.9	100.00 %
13	Continuity_PPMU1 p51 19.g149	P	−1200 mV	−100 mV	Samples	50	0	−636.962 mV	0.54028 mV	339.3	331.3	100.00 %
14	Continuity_PPMU1 p52 19.e137	P	−1200 mV	−100 mV	Samples	50	0	−638.95 mV	1.03487 mV	177.2	173.6	100.00 %
15	Continuity_PPMU1 p53 19.e135	P	−1200 mV	−100 mV	Samples	50	0	−638.98 mV	1.01611 mV	180.4	176.8	100.00 %
16	Continuity_PPMU1 p60 19.g130	P	−1200 mV	−100 mV	Samples	50	0	−638.487 mV	0.990124 mV	185.2	181.3	100.00 %
17	Continuity_PPMU1 p61 19.g104	P	−1200 mV	−100 mV	Samples	50	0	−638.587 mV	0.89431 mV	205.0	200.7	100.00 %
18	Continuity_PPMU1 p62 19.g102	P	−1200 mV	−100 mV	Samples	50	0	−638.714 mV	0.880006 mV	208.3	204.1	100.00 %
19	Continuity_PPMU1 p63 19.e102	P	−1200 mV	−100 mV	Samples	50	0	−638.59 mV	0.807409 mV	227.1	222.4	100.00 %
20	Continuity_PPMU1 p70 19.g139	P	−1200 mV	−100 mV	Samples	50	0	−640.607 mV	1.04313 mV	175.8	172.8	100.00 %
21	Continuity_PPMU1 p71 19.g147	P	−1200 mV	−100 mV	Samples	50	0	−639.025 mV	0.920964 mV	199.1	195.1	100.00 %
22	Continuity_PPMU1 p72 19.e104	P	−1200 mV	−100 mV	Samples	50	0	−638.391 mV	0.692156 mV	264.9	259.3	100.00 %
23	Continuity_PPMU1 p73 19.e108	P	−1200 mV	−100 mV	Samples	50	0	−638.347 mV	0.839341 mV	218.4	213.8	100.00 %
24	Continuity_PPMU1 prog 19.g124	P	−1200 mV	−100 mV	Samples	50	0	−640.355 mV	0.771775 mV	237.5	233.4	100.00 %
25	SeqLeakage1 p20 19.g128	P	−30 uA	10 uA	Samples	50	0	−0.643538 uA	0.0210859 uA	316.2	168.3	100.00 %
26	SeqLeakage1 p21 19.g126	P	−30 uA	10 uA	Samples	50	0	−0.644704 uA	0.0201149 uA	331.4	176.4	100.00 %
27	SeqLeakage1 p22 19.e126	P	−30 uA	10 uA	Samples	50	0	−0.645216 uA	0.0212512 uA	313.7	167.0	100.00 %
28	SeqLeakage1 p23 19.e124	P	−30 uA	10 uA	Samples	50	0	−0.649707 uA	0.0163203 uA	408.5	217.5	100.00 %
29	SeqLeakage2 cs 19.g106	P	−30 uA	10 uA	Samples	50	0	0.00377989 uA	0.0139168 uA	479.0	239.4	100.00 %
30	SeqLeakage2 prog 19.g124	P	−30 uA	10 uA	Samples	50	0	0.00239898 uA	0.0103091 uA	646.7	323.3	100.00 %
31	VBT_outpleakage1 p40 19.e130	P	−10 uA	20 uA	Samples	50	0	0.000153235 uA	0.00941589 uA	531.0	354.0	100.00 %
Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
32	VBT_outpleakage1 p41 19.e139	P	−10 uA	20 uA	Samples	50	0	0.00223532 uA	0.00995074 uA	502.5	335.1	100.00 %
33	VBT_outpleakage1 p42 19.e147	P	−10 uA	20 uA	Samples	50	0	0.00267875 uA	0.00934308 uA	535.2	356.9	100.00 %
34	VBT_outpleakage1 p43 19.e151	P	−10 uA	20 uA	Samples	50	0	0.000565724 uA	0.00804117 uA	621.8	414.6	100.00 %
35	VBT_outpleakage1 p50 19.e128	P	−10 uA	20 uA	Samples	50	0	0.00328891 uA	0.0100809 uA	496.0	330.8	100.00 %
36	VBT_outpleakage1 p51 19.g149	P	−10 uA	20 uA	Samples	50	0	0.00319883 uA	0.00982904 uA	508.7	339.2	100.00 %

Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
37	VBT_outpleakage1 p52 19.e137	P	−10 uA	20 uA	Samples	50	0	−0.00240455 uA	0.00898792 uA	556.3	370.8	100.00 %
38	VBT_outpleakage1 p53 19.e135	P	−10 uA	20 uA	Samples	50	0	0.000548436 uA	0.0111104 uA	450.0	300.0	100.00 %
39	VBT_outpleakage1 p60 19.g130	P	−10 uA	20 uA	Samples	50	0	−0.00307633 uA	0.00963114 uA	519.1	346.0	100.00 %
40	VBT_outpleakage1 p61 19.g104	P	−10 uA	20 uA	Samples	50	0	0.00232042 uA	0.0123971 uA	403.3	268.9	100.00 %
41	VBT_outpleakage1 p62 19.g102	P	−10 uA	20 uA	Samples	50	0	0.0050663 uA	0.011847 uA	422.0	281.5	100.00 %
42	VBT_outpleakage1 p63 19.e102	P	−10 uA	20 uA	Samples	50	0	0.00114381 uA	0.0138642 uA	360.6	240.5	100.00 %
43	VBT_outpleakage1 p70 19.g139	P	−10 uA	20 uA	Samples	50	0	−0.00199775 uA	0.0102119 uA	489.6	326.4	100.00 %
44	VBT_outpleakage1 p71 19.g147	P	−10 uA	20 uA	Samples	50	0	0.00360431 uA	0.00798614 uA	626.1	417.5	100.00 %
45	VBT_outpleakage1 p72 19.e104	P	−10 uA	20 uA	Samples	50	0	−0.000503117 uA	0.0104426 uA	478.8	319.2	100.00 %
46	VBT_outpleakage1 p73 19.e108	P	−10 uA	20 uA	Samples	50	0	0.00274413 uA	0.00986106 uA	507.0	338.1	100.00 %
47	OutputZ_leak_vbt1 p40 19.e130	P	−10 uA	20 uA	Samples	50	0	−0.000904088 uA	0.0110801 uA	451.3	300.8	100.00 %
48	OutputZ_leak_vbt1 p41 19.e139	P	−10 uA	20 uA	Samples	50	0	0.000811452 uA	0.00898859 uA	556.3	370.9	100.00 %
49	OutputZ_leak_vbt1 p42 19.e147	P	−10 uA	20 uA	Samples	50	0	0.00132416 uA	0.0103129 uA	484.8	323.3	100.00 %
50	OutputZ_leak_vbt1 p43 19.e151	P	−10 uA	20 uA	Samples	50	0	0.0013455 uA	0.010356 uA	482.8	321.9	100.00 %
51	OutputZ_leak_vbt1 p50 19.e128	P	−10 uA	20 uA	Samples	50	0	0.00424818 uA	0.00919896 uA	543.5	362.5	100.00 %
52	OutputZ_leak_vbt1 p51 19.g149	P	−10 uA	20 uA	Samples	50	0	−0.000780576 uA	0.010619 uA	470.9	313.9	100.00 %
53	OutputZ_leak_vbt1 p52 19.e137	P	−10 uA	20 uA	Samples	50	0	−0.000382891 uA	0.0100648 uA	496.8	331.2	100.00 %
54	OutputZ_leak_vbt1 p53 19.e135	P	−10 uA	20 uA	Samples	50	0	−0.00233085 uA	0.00951285 uA	525.6	350.3	100.00 %
55	OutputZ_leak_vbt1 p60 19.g130	P	−10 uA	20 uA	Samples	50	0	−0.00074995 uA	0.00887369 uA	563.5	375.6	100.00 %
56	OutputZ_leak_vbt1 p61 19.g104	P	−10 uA	20 uA	Samples	50	0	0.00233569 uA	0.0109506 uA	456.6	304.5	100.00 %
57	OutputZ_leak_vbt1 p62 19.g102	P	−10 uA	20 uA	Samples	50	0	0.00656629 uA	0.015793 uA	316.6	211.2	100.00 %
58	OutputZ_leak_vbt1 p63 19.e102	P	−10 uA	20 uA	Samples	50	0	0.00256213 uA	0.0095701 uA	522.5	348.4	100.00 %
59	OutputZ_leak_vbt1 p70 19.g139	P	−10 uA	20 uA	Samples	50	0	−0.00340074 uA	0.0083632 uA	597.9	398.4	100.00 %
60	OutputZ_leak_vbt1 p71 19.g147	P	−10 uA	20 uA	Samples	50	0	0.00473928 uA	0.00969933 uA	515.5	343.8	100.00 %
61	OutputZ_leak_vbt1 p72 19.e104	P	−10 uA	20 uA	Samples	50	0	9.14757e−05 uA	0.014236 uA	351.2	234.1	100.00 %
62	OutputZ_leak_vbt1 p73 19.e108	P	−10 uA	20 uA	Samples	50	0	0.00481746 uA	0.00924571 uA	540.8	360.7	100.00 %
63	func_T4	F	n/a .	n/a .	Samples	50	0	n/a .	n/a .	n/a .	n/a .	100.00 %
Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
64	icc_static_vbt11 vcc 15.e201 <> Icc_static	P	10 uA	500 uA	Samples	50	0	21.2368 uA	0.265376 uA	307.7	14.11	100.00 %
65	Icc_dynamic vcc 15.e201 <> Icc_dynamic	P	10 uA	500 uA	Samples	50	0	20.7115 uA	0.279655 uA	292.0	12.77	100.00 %
67	func_T5 p50 19.e128	P	n/a .	n/a .	Samples	50	0	0.14566	0.00213436	n/a .	n/a .	100.00 %
68	func_T5 p50 19.e128	P	n/a .	n/a .	Samples	50	0	3.28286	0.0020604	n/a .	n/a .	100.00 %
71	func_T6 p50 19.e128	P	150 ns	350 ns	Samples	50	0	231 ns	0.875051 ns	38.09	30.86	100.00 %
72	func_T6 p50 19.e128	P	150 ns	350 ns	Samples	50	0	246.624 ns	0.808767 ns	41.21	39.82	100.00 %
73	func_T6 A8 0	P	1 ns	100 ns	Samples	50	0	15.624 ns	1.11219 ns	14.84	4.38	100.00 %
75	func_T7 p53 19.e135	P	n/a .	n/a .	Samples	50	0	3.28324 V	0.00187966 V	n/a .	n/a .	100.00 %
76	func_T7 p53 19.e135	P	n/a .	n/a .	Samples	50	0	0.13934	0.00244624	n/a .	n/a .	100.00 %
81	func_T8 A8 0	P	1 ns	20 ns	Samples	50	0	9.336 ns	1.26648 ns	2.50	2.19	100.00 %
786000	Soft_Bin parameter	–	n/a .	n/a .	Samples	50	0	1	0	n/a .	n/a .	100.00 %
786001	Hard_Bin parameter	–	n/a .	n/a .	Samples	50	0	1	0	n/a .	n/a .	100.00 %
786002	Die_X parameter	–	n/a .	n/a .	Samples	50	0	2.94	2.0445	n/a .	n/a .	100.00 %
786003	Die_Y parameter	–	n/a .	n/a .	Samples	50	0	3.92	2.07846	n/a .	n/a .	100.00 %
786004	Test_Time parameter	–	0.0 sec	n/a .	Samples	50	0	2.89756 sec	0.0315738 sec	n/a .	30.59	100.00 %
786006	Testing_Site parameter	–	n/a .	n/a .	Samples	50	0	0	0	n/a .	n/a .	100.00 %
786007	Part_ID parameter	–	n/a .	n/a .	Samples	50	0	29.5	14.5774	n/a .	n/a .	100.00 %

Histogram of Tests

Test	3
Name	Continuity_PPMU1 cs 19.g106
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−639.204 mV
Sigma	0.59363 mV
Range	2.44224 mV
Cp / Cpk	308.8 / 302.8
Samples	50

Test 3: Continuity_PPMU1 cs 19.g106

Test	4
Name	Continuity_PPMU1 p20 19.g128
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−640.382 mV
Sigma	0.96489 mV
Range	4.27341 mV
Cp / Cpk	190.0 / 186.7
Samples	50
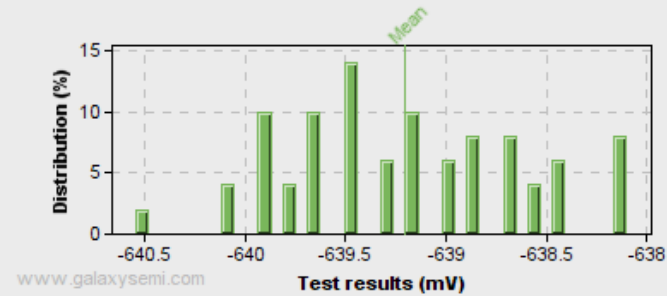
Test 4: Continuity_PPMU1 p20 19.g128
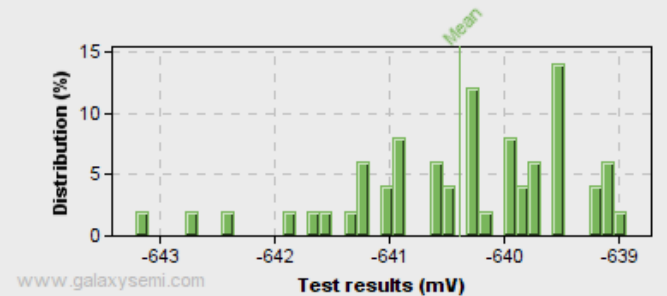
Test	5
Name	Continuity_PPMU1 p21 19.g126
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−640.401 mV
Sigma	0.899843 mV
Range	4.12118 mV
Cp / Cpk	203.7 / 200.2
Samples	50

Test 5: Continuity_PPMU1 p21 19.g126
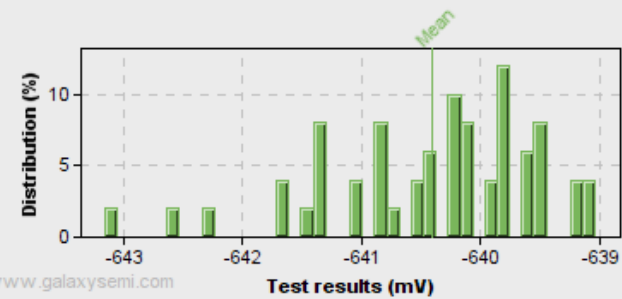
Test	6
Name	Continuity_PPMU1 p22 19.e126
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−640.346 mV
Sigma	0.835683 mV
Range	3.96746 mV
Cp / Cpk	219.4 / 215.5
Samples	50

Test 6: Continuity_PPMU1 p22 19.e126

Histogram of Tests
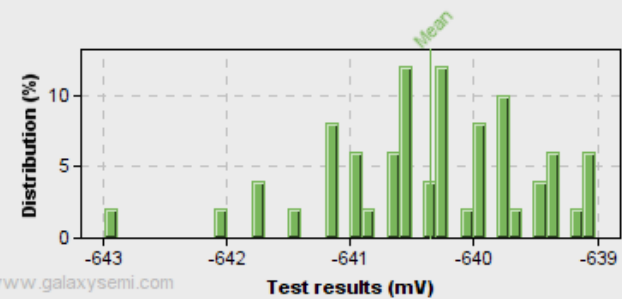
Test	7
Name	Continuity_PPMU1 p23 19.e124
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−640.312 mV
Sigma	0.820142 mV
Range	3.51036 mV
Cp / Cpk	223.5 / 219.6
Samples	50
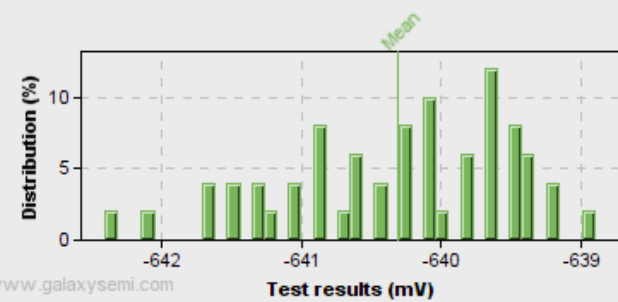
Test	8
Name	Continuity_PPMU1 p40 19.e130
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−641.037 mV
Sigma	0.995041 mV
Range	4.57817 mV
Cp / Cpk	184.2 / 181.2
Samples	50
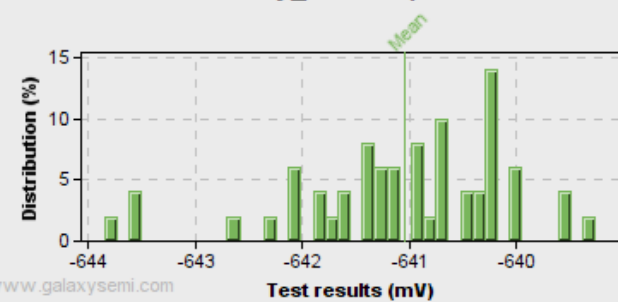
Test	9
Name	Continuity_PPMU1 p41 19.e139
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−641.138 mV
Sigma	1.06819 mV
Range	4.42612 mV
Cp / Cpk	171.6 / 168.9
Samples	50

Test 9: Continuity_PPMU1 p41 19.e139
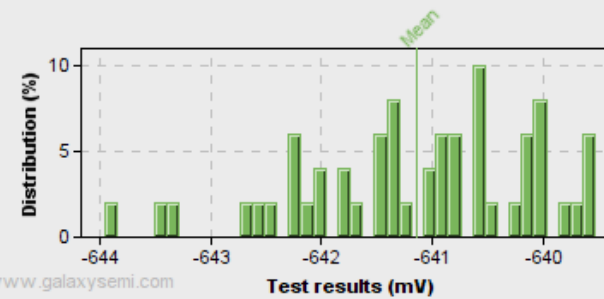
Test	10
Name	Continuity_PPMU1 p42 19.e147
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−641.359 mV
Sigma	0.884027 mV
Range	3.50982 mV
Cp / Cpk	207.4 / 204.1
Samples	50

Test 10: Continuity_PPMU1 p42 19.e147

Histogram of Tests
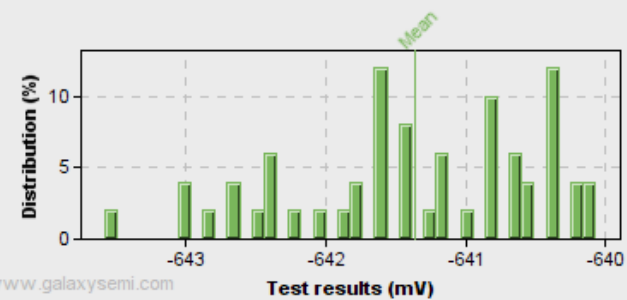
Test	11
Name	Continuity_PPMU1 p43 19.e151
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−641.045 mV
Sigma	0.90153 mV
Range	3.97044 mV
Cp / Cpk	203.4 / 200.0
Samples	50
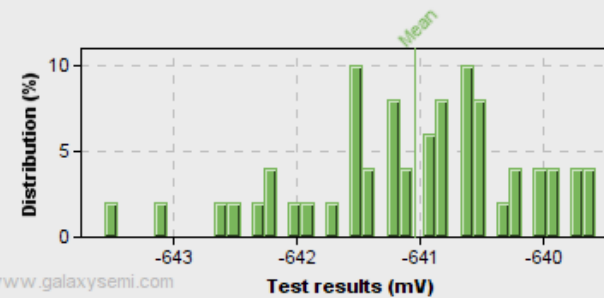
Test	12
Name	Continuity_PPMU1 p50 19.e128
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−640.299 mV
Sigma	1.02957 mV
Range	4.58056 mV
Cp / Cpk	178.1 / 174.9
Samples	50
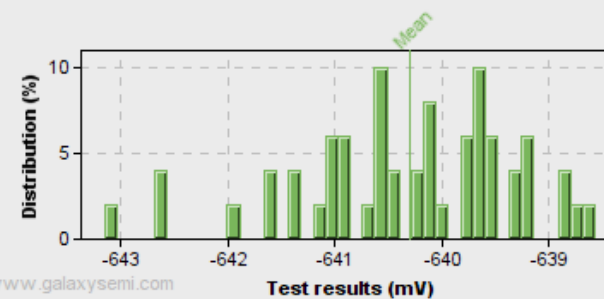
Test	13
Name	Continuity_PPMU1 p51 19.g149
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−636.962 mV
Sigma	0.54028 mV
Range	2.13647 mV
Cp / Cpk	339.3 / 331.3
Samples	50

Test 13: Continuity_PPMU1 p51 19.g149
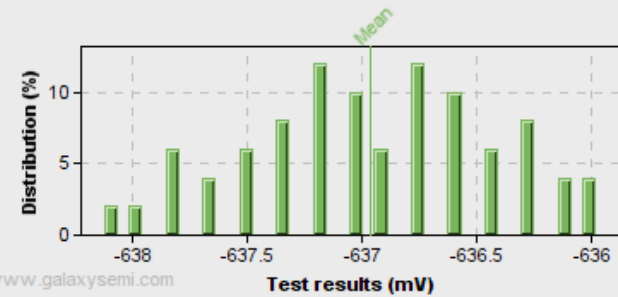
Test	14
Name	Continuity_PPMU1 p52 19.e137
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−638.95 mV
Sigma	1.03487 mV
Range	4.88514 mV
Cp / Cpk	177.2 / 173.6
Samples	50

Test 14: Continuity_PPMU1 p52 19.e137

Histogram of Tests
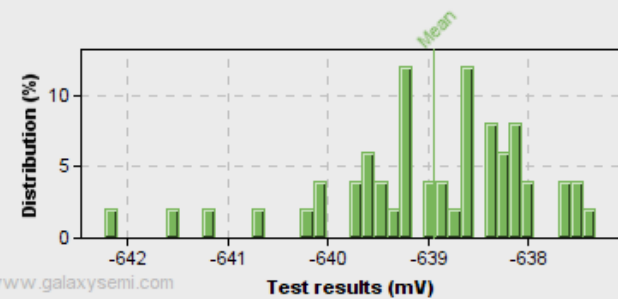
Test	15
Name	Continuity_PPMU1 p53 19.e135
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−638.98 mV
Sigma	1.01611 mV
Range	4.88287 mV
Cp / Cpk	180.4 / 176.8
Samples	50
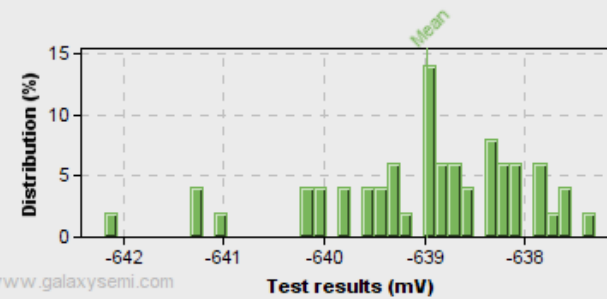
Test	16
Name	Continuity_PPMU1 p60 19.g130
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−638.487 mV
Sigma	0.990124 mV
Range	4.4263 mV
Cp / Cpk	185.2 / 181.3
Samples	50
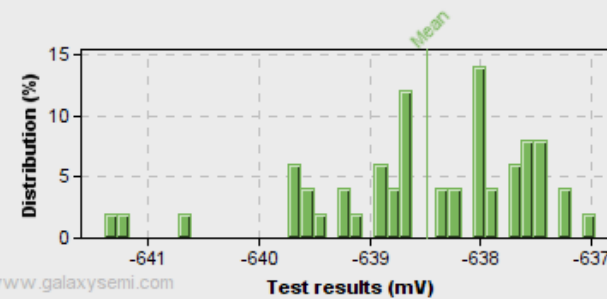
Test	17
Name	Continuity_PPMU1 p61 19.g104
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−638.587 mV
Sigma	0.89431 mV
Range	3.81547 mV
Cp / Cpk	205.0 / 200.7
Samples	50

Test 17: Continuity_PPMU1 p61 19.g104
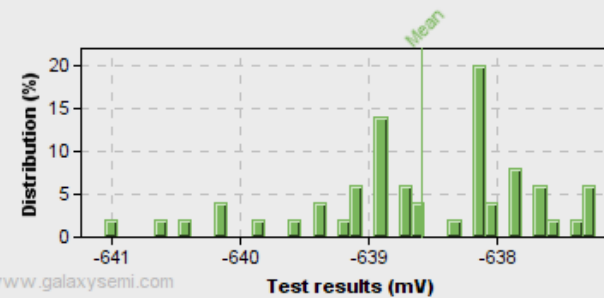
Test	18
Name	Continuity_PPMU1 p62 19.g102
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−638.714 mV
Sigma	0.880006 mV
Range	3.81535 mV
Cp / Cpk	208.3 / 204.1
Samples	50

Test 18: Continuity_PPMU1 p62 19.g102

Histogram of Tests
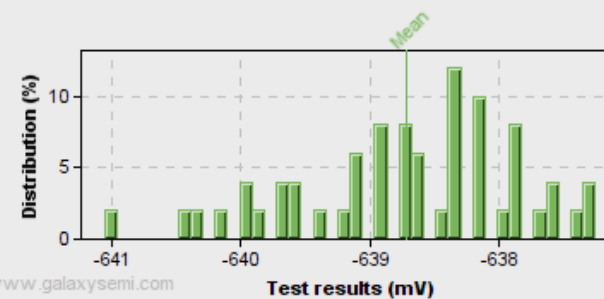
Test	19
Name	Continuity_PPMU1 p63 19.e102
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−638.59 mV
Sigma	0.807409 mV
Range	3.5094 mV
Cp / Cpk	227.1 / 222.4
Samples	50

Test 19: Continuity_PPMU1 p63 19.e102
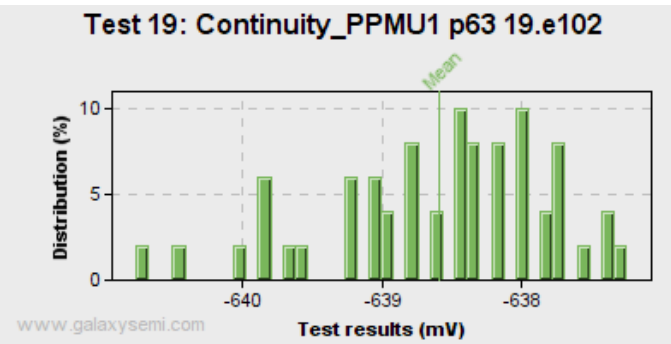
Test	20
Name	Continuity_PPMU1 p70 19.g139
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−640.607 mV
Sigma	1.04313 mV
Range	4.42702 mV
Cp / Cpk	175.8 / 172.8
Samples	50

Test 20: Continuity_PPMU1 p70 19.g139

Histogram of Tests
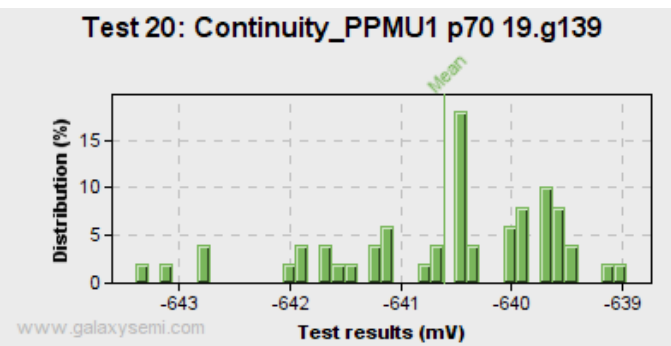
Test	21
Name	Continuity_PPMU1 p71 19.g147
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−639.025 mV
Sigma	0.920964 mV
Range	3.66348 mV
Cp / Cpk	199.1 / 195.1
Samples	50

Test 21: Continuity_PPMU1 p71 19.g147
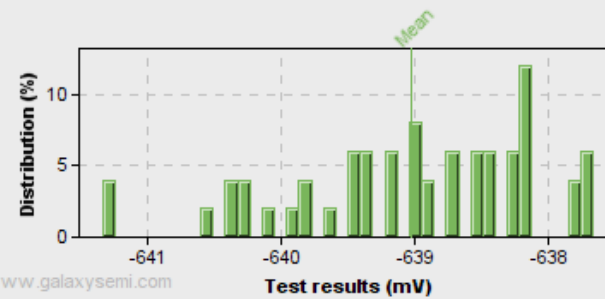
Test	22
Name	Continuity_PPMU1 p72 19.e104
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−638.391 mV
Sigma	0.692156 mV
Range	3.20596 mV
Cp / Cpk	264.9 / 259.3
Samples	50

Test 22: Continuity_PPMU1 p72 19.e104

Histogram of Tests
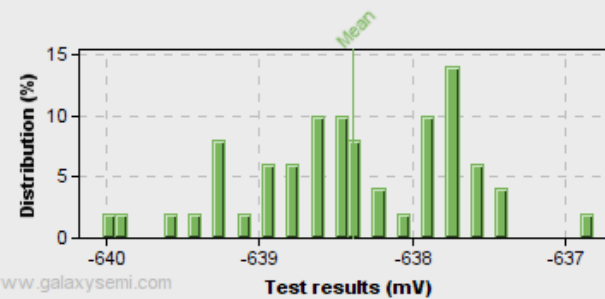
Test	23
Name	Continuity_PPMU1 p73 19.e108
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−638.347 mV
Sigma	0.839341 mV
Range	3.50994 mV
Cp / Cpk	218.4 / 213.8
Samples	50

Test 23: Continuity_PPMU1 p73 19.e108
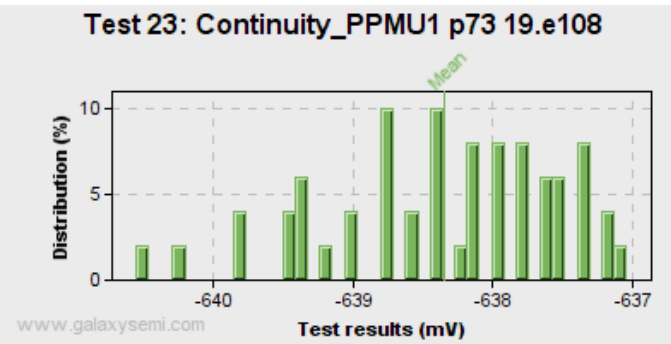
Test	24
Name	Continuity_PPMU1 prog 19.g124
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−640.355 mV
Sigma	0.771775 mV
Range	3.20476 mV
Cp / Cpk	237.5 / 233.4
Samples	50

Test 24: Continuity_PPMU1 prog 19.g124

Histogram of Tests
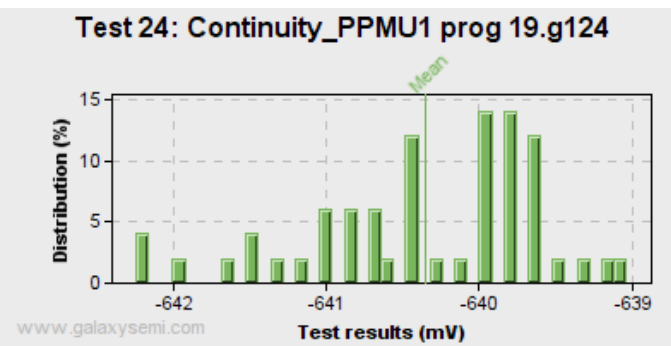
Test	25
Name	SeqLeakage1 p20 19.g128
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.643538 uA
Sigma	0.0210859 uA
Range	0.0937636 uA
Cp / Cpk	316.2 / 168.3
Samples	50

Test 25: SeqLeakage1 p20 19.g128
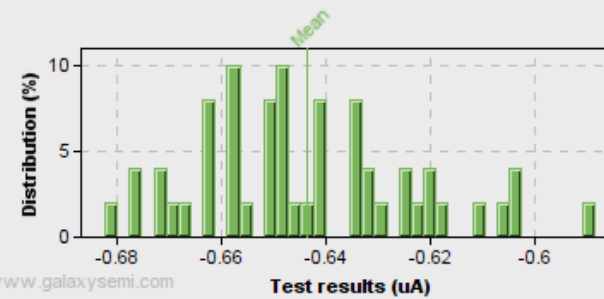
Test	26
Name	SeqLeakage1 p21 19.g126
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.644704 uA
Sigma	0.0201149 uA
Range	0.104125 uA
Cp / Cpk	331.4 / 176.4
Samples	50

Test 26: SeqLeakage1 p21 19.g126

Histogram of Tests
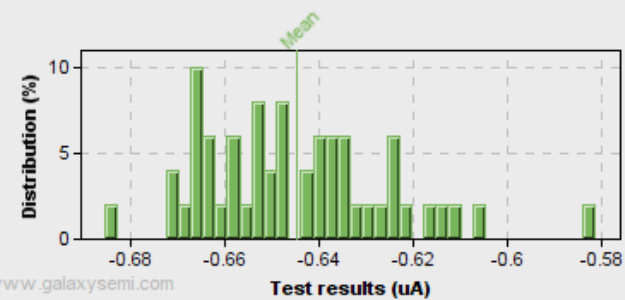
Test	27
Name	SeqLeakage1 p22 19.e126
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.645216 uA
Sigma	0.0212512 uA
Range	0.0964403 uA
Cp / Cpk	313.7 / 167.0
Samples	50
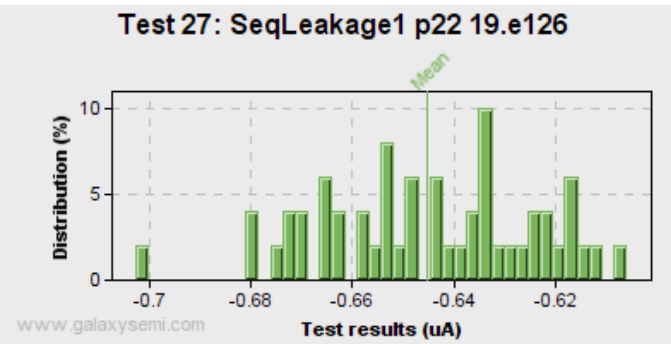
Test	28
Name	SeqLeakage1 p23 19.e124
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.649707 uA
Sigma	0.0163203 uA
Range	0.0732425 uA
Cp / Cpk	408.5 / 217.5
Samples	50

Histogram of Tests
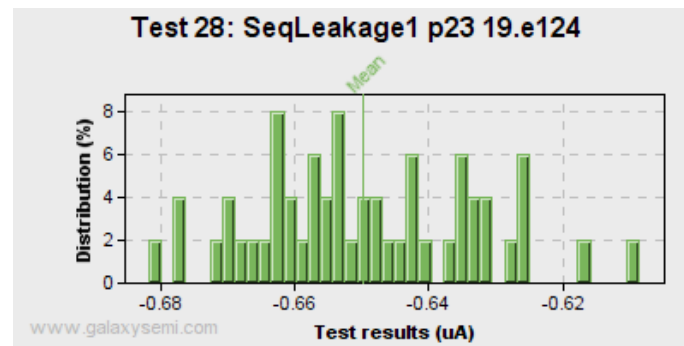
Test	29
Name	SeqLeakage2 cs 19.g106
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00377989 uA
Sigma	0.0139168 uA
Range	0.0872283 uA
Cp / Cpk	479.0 / 239.4
Samples	50

Test 29: SeqLeakage2 cs 19.g106
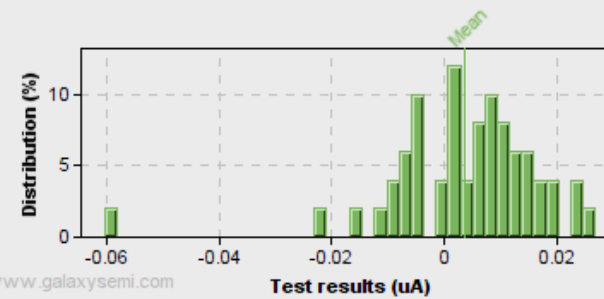
Test	30
Name	SeqLeakage2 prog 19.g124
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00239898 uA
Sigma	0.0103091 uA
Range	0.0466044 uA
Cp / Cpk	646.7 / 323.3
Samples	50

Test 30: SeqLeakage2 prog 19.g124

Histogram of Tests
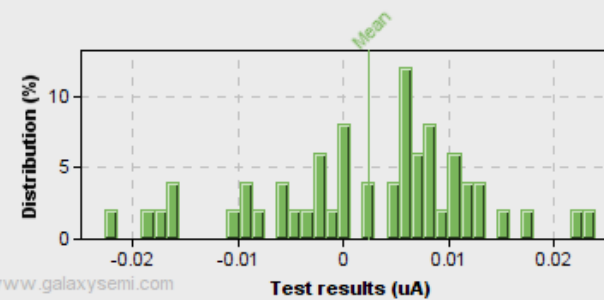
Test	31
Name	VBT_outpleakage1 p40 19.e130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.000153235 uA
Sigma	0.00941589 uA
Range	0.0352441 uA
Cp / Cpk	531.0 / 354.0
Samples	50
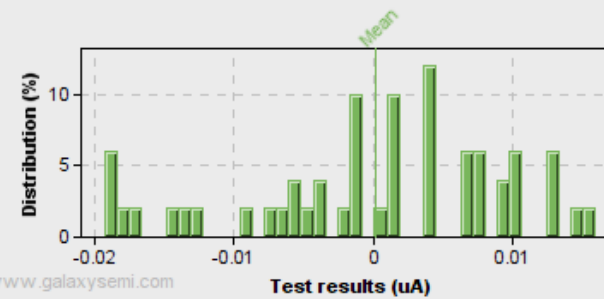
Test	32
Name	VBT_outpleakage1 p41 19.e139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00223532 uA
Sigma	0.00995074 uA
Range	0.0421036 uA
Cp / Cpk	502.5 / 335.1
Samples	50
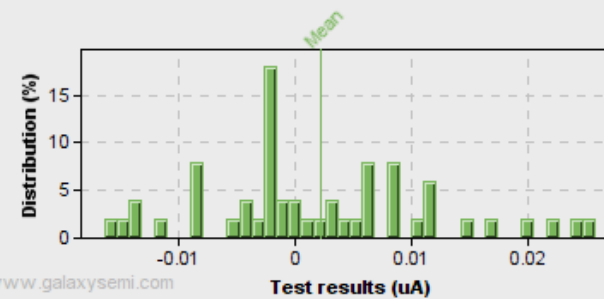
Test	33
Name	VBT_outpleakage1 p42 19.e147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00267875 uA
Sigma	0.00934308 uA
Range	0.0547927 uA
Cp / Cpk	535.2 / 356.9
Samples	50

Test 33: VBT_outpleakage1 p42 19.e147
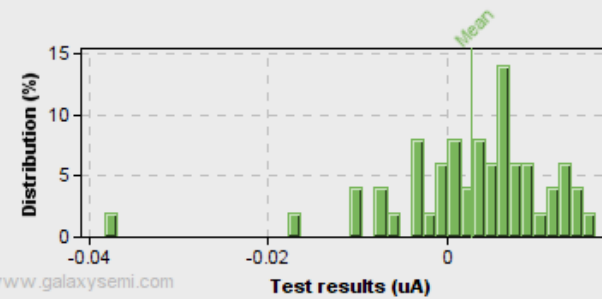
Test	34
Name	VBT_outpleakage1 p43 19.e151
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.000565724 uA
Sigma	0.00804117 uA
Range	0.0313441 uA
Cp / Cpk	621.8 / 414.6
Samples	50

Test 34: VBT_outpleakage1 p43 19.e151

Histogram of Tests
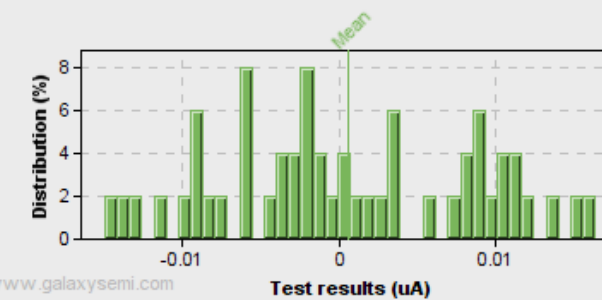
Test	35
Name	VBT_outpleakage1 p50 19.e128
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00328891 uA
Sigma	0.0100809 uA
Range	0.0540539 uA
Cp / Cpk	496.0 / 330.8
Samples	50
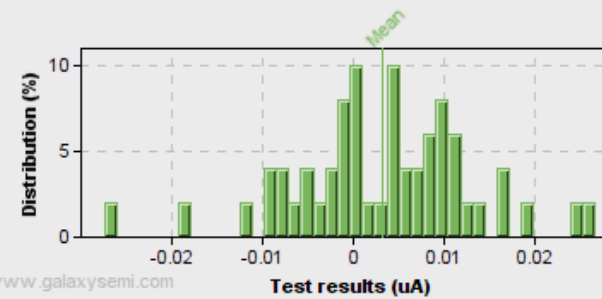
Test	36
Name	VBT_outpleakage1 p51 19.g149
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00319883 uA
Sigma	0.00982904 uA
Range	0.0420899 uA
Cp / Cpk	508.7 / 339.2
Samples	50

Histogram of Tests
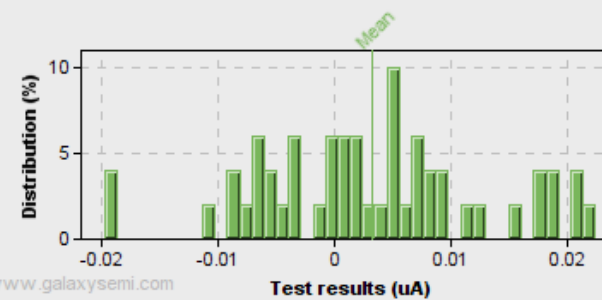
Test	37
Name	VBT_outpleakage1 p52 19.e137
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00240455 uA
Sigma	0.00898792 uA
Range	0.0436495 uA
Cp / Cpk	556.3 / 370.8
Samples	50

Test 37: VBT_outpleakage1 p52 19.e137
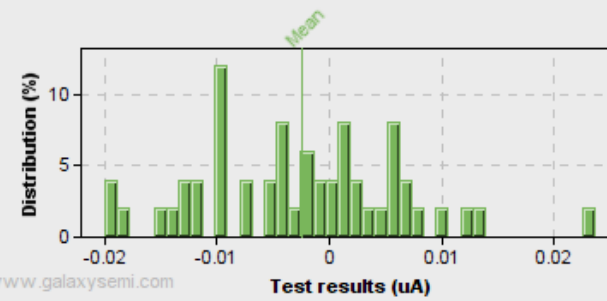
Test	38
Name	VBT_outpleakage1 p53 19.e135
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.000548436 uA
Sigma	0.0111104 uA
Range	0.0525585 uA
Cp / Cpk	450.0 / 300.0
Samples	50

Test 38: VBT_outpleakage1 p53 19.e135

Histogram of Tests
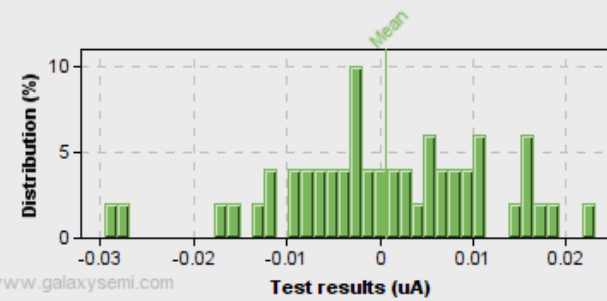
Test	39
Name	VBT_outpleakage1 p60 19.g130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00307633 uA
Sigma	0.00963114 uA
Range	0.0543331 uA
Cp / Cpk	519.1 / 346.0
Samples	50

Test 39: VBT_outpleakage1 p60 19.g130
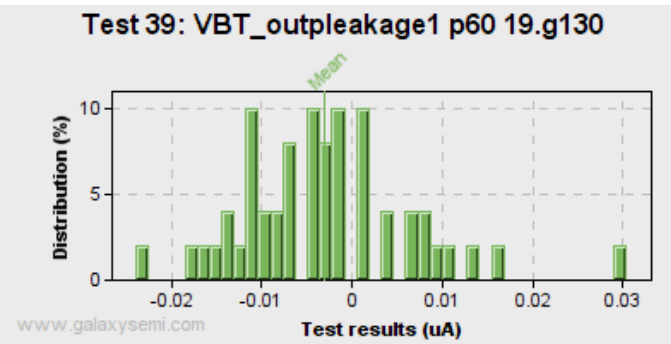
Test	40
Name	VBT_outpleakage1 p61 19.g104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00232042 uA
Sigma	0.0123971 uA
Range	0.0801462 uA
Cp / Cpk	403.3 / 268.9
Samples	50

Test 40: VBT_outpleakage1 p61 19.g104

Histogram of Tests
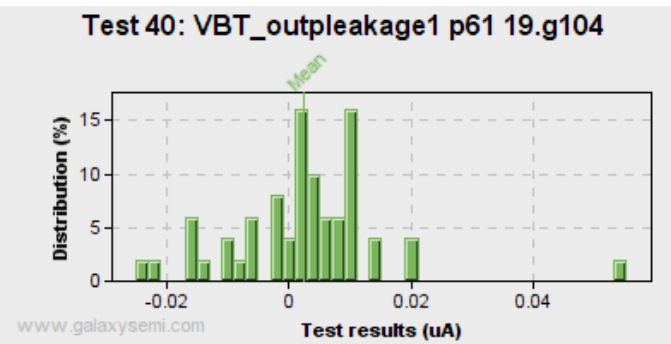
Test	41
Name	VBT_outpleakage1 p62 19.g102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.0050663 uA
Sigma	0.011847 uA
Range	0.0749996 uA
Cp / Cpk	422.0 / 281.5
Samples	50
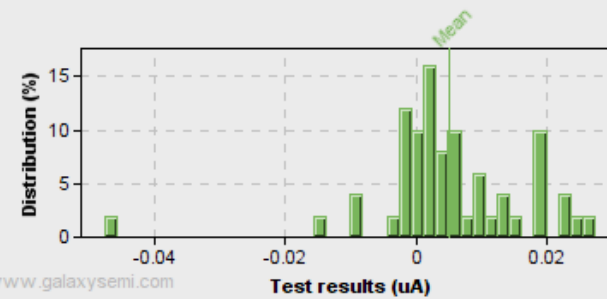
Test	42
Name	VBT_outpleakage1 p63 19.e102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00114381 uA
Sigma	0.0138642 uA
Range	0.0884544 uA
Cp / Cpk	360.6 / 240.5
Samples	50

Histogram of Tests
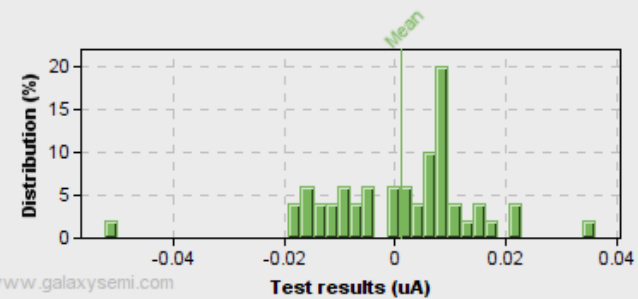
Test	43
Name	VBT_outpleakage1 p70 19.g139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00199775 uA
Sigma	0.0102119 uA
Range	0.0449874 uA
Cp / Cpk	489.6 / 326.4
Samples	50

Test 43: VBT_outpleakage1 p70 19.g139
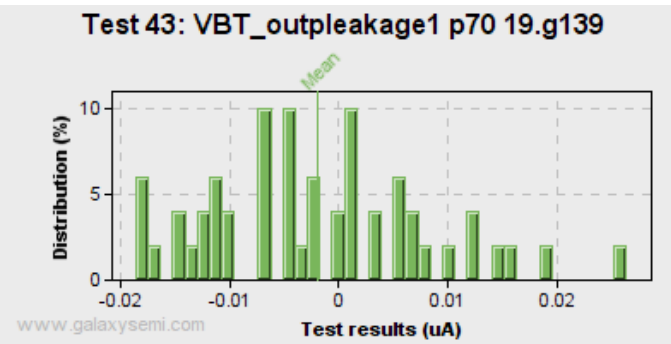
Test	44
Name	VBT_outpleakage1 p71 19.g147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00360431 uA
Sigma	0.00798614 uA
Range	0.0429449 uA
Cp / Cpk	626.1 / 417.5
Samples	50

Test 44: VBT_outpleakage1 p71 19.g147

Histogram of Tests
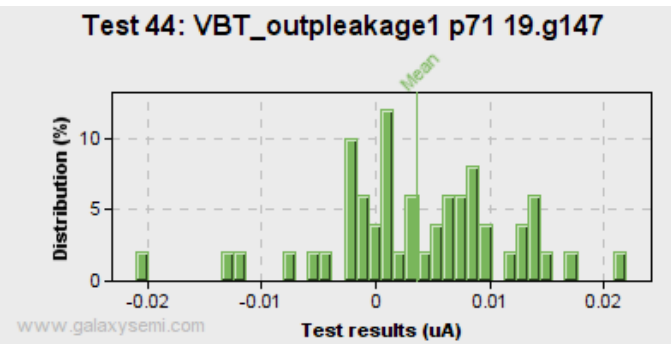
Test	45
Name	VBT_outpleakage1 p72 19.e104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.000503117 uA
Sigma	0.0104426 uA
Range	0.0548855 uA
Cp / Cpk	478.8 / 319.2
Samples	50

Test 45: VBT_outpleakage1 p72 19.e104
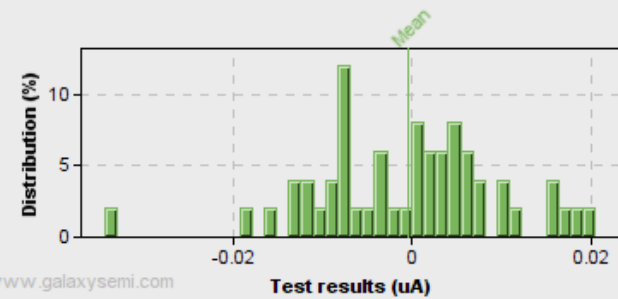
Test	46
Name	VBT_outpleakage1 p73 19.e108
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00274413 uA
Sigma	0.00986106 uA
Range	0.0609806 uA
Cp / Cpk	507.0 / 338.1
Samples	50

Test 46: VBT_outpleakage1 p73 19.e108

Histogram of Tests
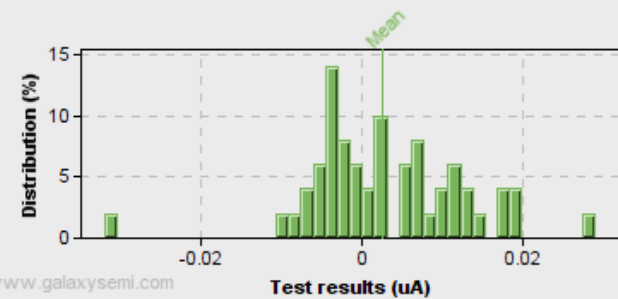
Test	47
Name	OutputZ_leak_vbt1 p40 19.e130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.000904088 uA
Sigma	0.0110801 uA
Range	0.0574632 uA
Cp / Cpk	451.3 / 300.8
Samples	50

Test 47: OutputZ_leak_vbt1 p40 19.e130
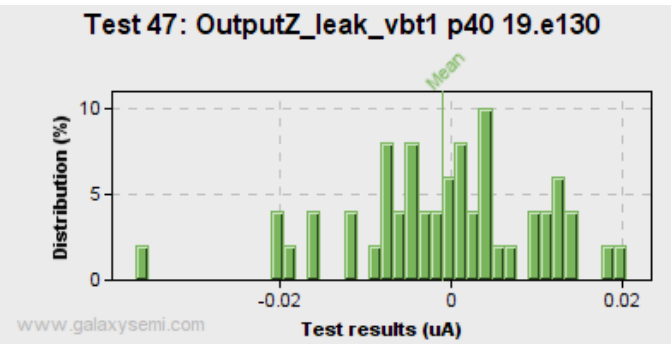
Test	48
Name	OutputZ_leak_vbt1 p41 19.e139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.000811452 uA
Sigma	0.00898859 uA
Range	0.0428692 uA
Cp / Cpk	556.3 / 370.9
Samples	50

Test 48: OutputZ_leak_vbt1 p41 19.e139

Histogram of Tests
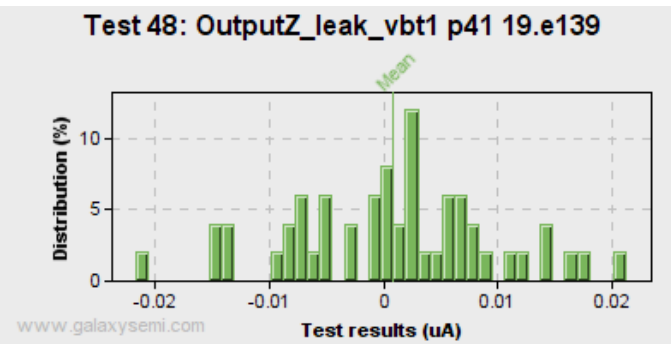
Test	49
Name	OutputZ_leak_vbt1 p42 19.e147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00132416 uA
Sigma	0.0103129 uA
Range	0.0448996 uA
Cp / Cpk	484.8 / 323.3
Samples	50

Test 49: OutputZ_leak_vbt1 p42 19.e147
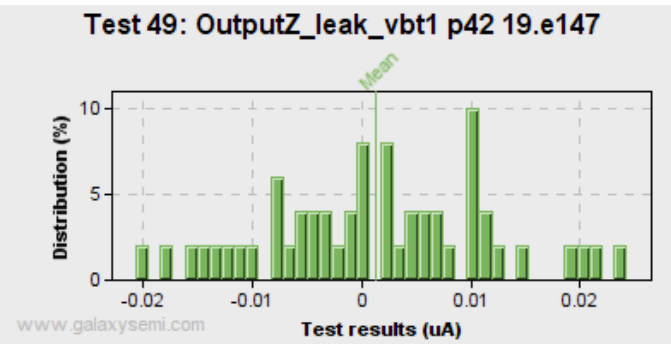
Test	50
Name	OutputZ_leak_vbt1 p43 19.e151
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.0013455 uA
Sigma	0.010356 uA
Range	0.0389891 uA
Cp / Cpk	482.8 / 321.9
Samples	50

Test 50: OutputZ_leak_vbt1 p43 19.e151

Histogram of Tests
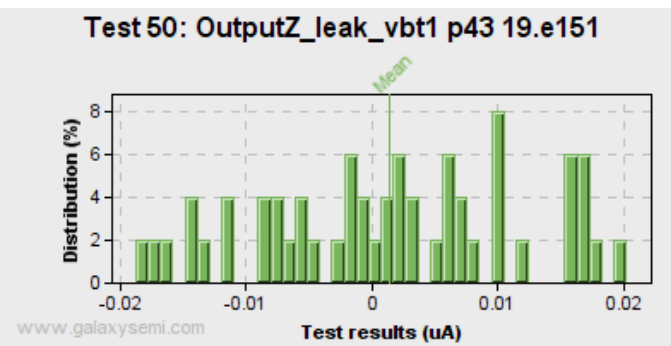
Test	51
Name	OutputZ_leak_vbt1 p50 19.e128
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00424818 uA
Sigma	0.00919896 uA
Range	0.0395888 uA
Cp / Cpk	543.5 / 362.5
Samples	50

Test 51: OutputZ_leak_vbt1 p50 19.e128
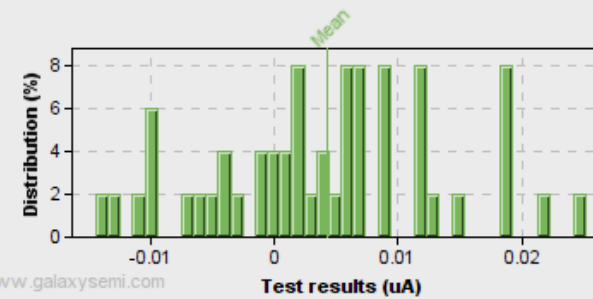
Test	52
Name	OutputZ_leak_vbt1 p51 19.g149
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.000780576 uA
Sigma	0.010619 uA
Range	0.0443857 uA
Cp / Cpk	470.9 / 313.9
Samples	50

Test 52: OutputZ_leak_vbt1 p51 19.g149

Histogram of Tests
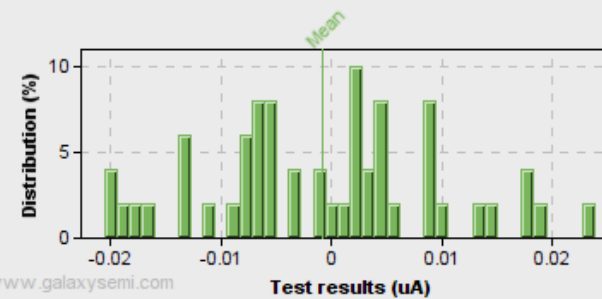
Test	53
Name	OutputZ_leak_vbt1 p52 19.e137
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.000382891 uA
Sigma	0.0100648 uA
Range	0.0513073 uA
Cp / Cpk	496.8 / 331.2
Samples	50
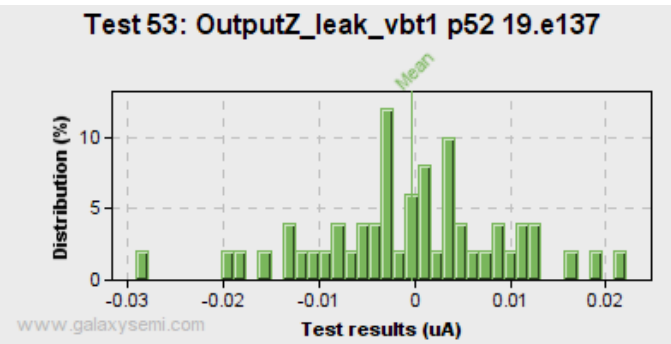
Test	54
Name	OutputZ_leak_vbt1 p53 19.e135
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00233085 uA
Sigma	0.00951285 uA
Range	0.0449413 uA
Cp / Cpk	525.6 / 350.3
Samples	50

Histogram of Tests
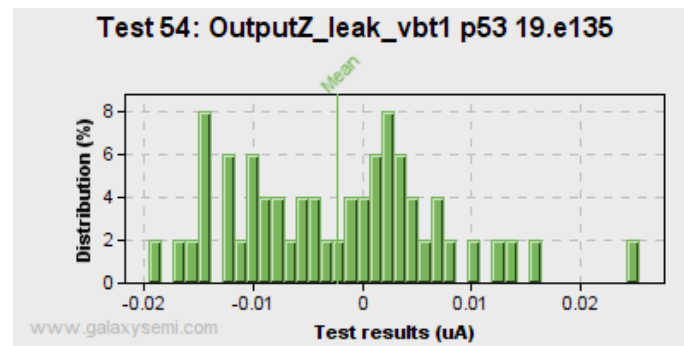
Test	55
Name	OutputZ_leak_vbt1 p60 19.g130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00074995 uA
Sigma	0.00887369 uA
Range	0.0352017 uA
Cp / Cpk	563.5 / 375.6
Samples	50

Test 55: OutputZ_leak_vbt1 p60 19.g130
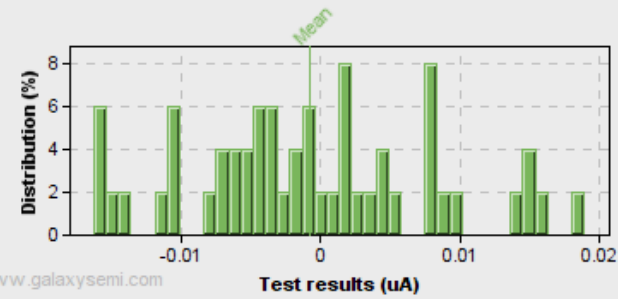
Test	56
Name	OutputZ_leak_vbt1 p61 19.g104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00233569 uA
Sigma	0.0109506 uA
Range	0.0740398 uA
Cp / Cpk	456.6 / 304.5
Samples	50

Test 56: OutputZ_leak_vbt1 p61 19.g104
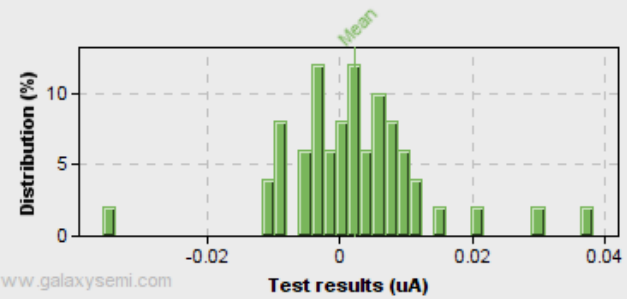
Test	57
Name	OutputZ_leak_vbt1 p62 19.g102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00656629 uA
Sigma	0.015793 uA
Range	0.0971933 uA
Cp / Cpk	316.6 / 211.2
Samples	50

Test 57: OutputZ_leak_vbt1 p62 19.g102
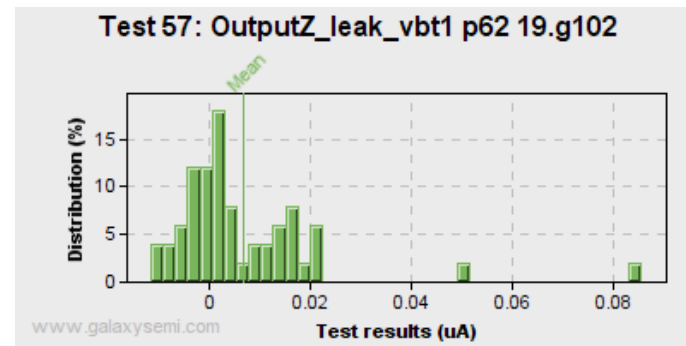
Test	58
Name	OutputZ_leak_vbt1 p63 19.e102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00256213 uA
Sigma	0.0095701 uA
Range	0.0549027 uA
Cp / Cpk	522.5 / 348.4
Samples	50

Test 58: OutputZ_leak_vbt1 p63 19.e102

Histogram of Tests
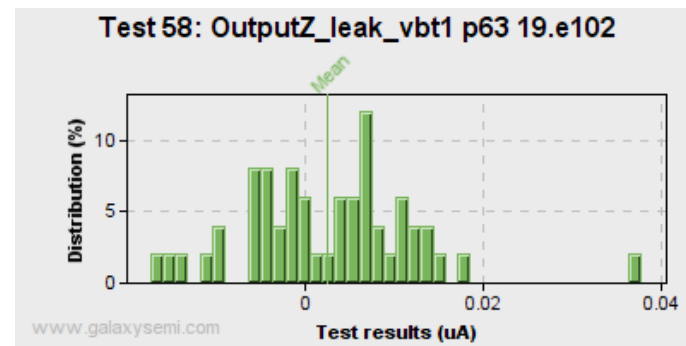
Test	59
Name	OutputZ_leak_vbt1 p70 19.g139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00340074 uA
Sigma	0.0083632 uA
Range	0.0404124 uA
Cp / Cpk	597.9 / 398.4
Samples	50

Test 59: OutputZ_leak_vbt1 p70 19.g139
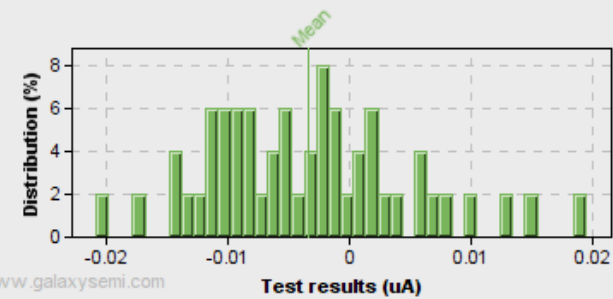
Test	60
Name	OutputZ_leak_vbt1 p71 19.g147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00473928 uA
Sigma	0.00969933 uA
Range	0.0613499 uA
Cp / Cpk	515.5 / 343.8
Samples	50

Test 60: OutputZ_leak_vbt1 p71 19.g147

Histogram of Tests
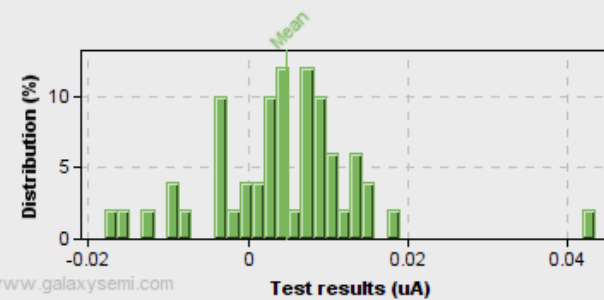
Test	61
Name	OutputZ_leak_vbt1 p72 19.e104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	9.14757e−05 uA
Sigma	0.014236 uA
Range	0.0785167 uA
Cp / Cpk	351.2 / 234.1
Samples	50

Test 61: OutputZ_leak_vbt1 p72 19.e104
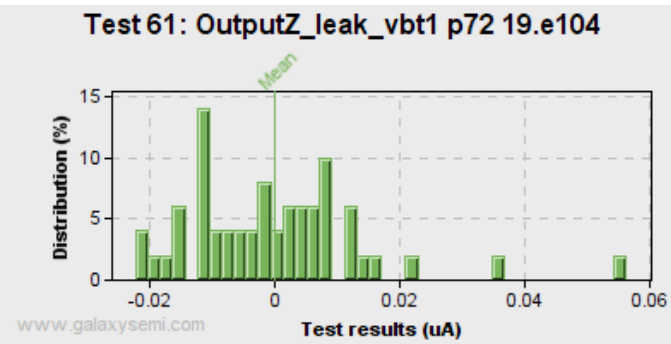
Test	62
Name	OutputZ_leak_vbt1 p73 19.e108
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00481746 uA
Sigma	0.00924571 uA
Range	0.050309 uA
Cp / Cpk	540.8 / 360.7
Samples	50

Test 62: OutputZ_leak_vbt1 p73 19.e108

Histogram of Tests
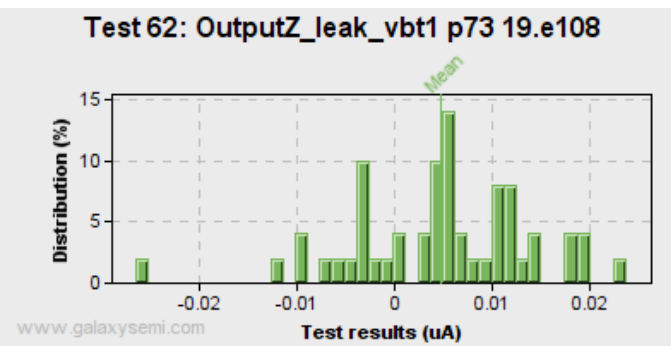
Test	64
Name	icc_static_vbt11 vcc 15.e201 <> Icc_static
Test type	Parametric
Low limit	10 uA
High limit	500 uA
Exec / Fails	50 / 0 (0.00%)
Mean	21.2368 uA
Sigma	0.265376 uA
Range	1.80244 uA
Cp / Cpk	307.7 / 14.11
Samples	50

Test 64: icc_static_vbt11 vcc 15.e201 <> Icc_static
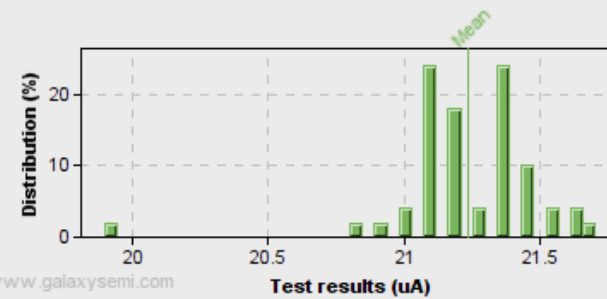
Test	65
Name	Icc_dynamic vcc 15.e201 <> Icc_dynamic
Test type	Parametric
Low limit	10 uA
High limit	500 uA
Exec / Fails	50 / 0 (0.00%)
Mean	20.7115 uA
Sigma	0.279655 uA
Range	1.71661 uA
Cp / Cpk	292.0 / 12.77
Samples	50

Test 65: Icc_dynamic vcc 15.e201 <> Icc_dynamic

Histogram of Tests
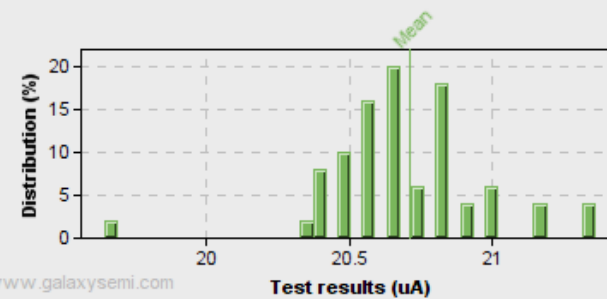
Test	67
Name	func_T5 p50 19.e128
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	0.14566
Sigma	0.00213436
Range	0.008
Cp / Cpk	n/a . / n/a .
Samples	50

Test 67: func_T5 p50 19.e128
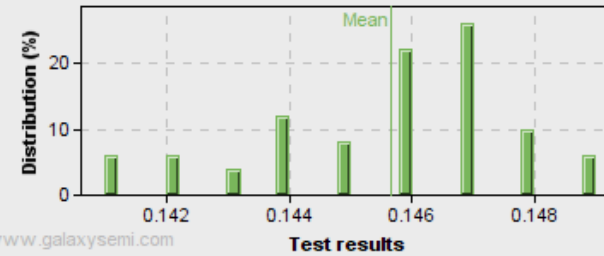
Test	68
Name	func_T5 p50 19.e128
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	3.28286
Sigma	0.0020604
Range	0.00899982
Cp / Cpk	n/a . / n/a .
Samples	50

Test 68: func_T5 p50 19.e128

Histogram of Tests
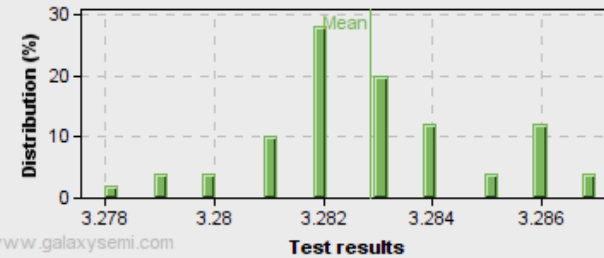
Test	71
Name	func_T6 p50 19.e128
Test type	Parametric
Low limit	150 ns
High limit	350 ns
Exec / Fails	50 / 0 (0.00%)
Mean	231 ns
Sigma	0.875051 ns
Range	2.79999 ns
Cp / Cpk	38.09 / 30.86
Samples	50

Test 71: func_T6 p50 19.e128
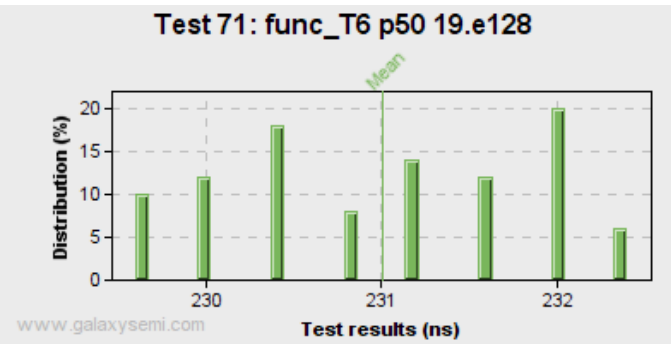
Test	72
Name	func_T6 p50 19.e128
Test type	Parametric
Low limit	150 ns
High limit	350 ns
Exec / Fails	50 / 0 (0.00%)
Mean	246.624 ns
Sigma	0.808767 ns
Range	3.2 ns
Cp / Cpk	41.21 / 39.82
Samples	50

Test 72: func_T6 p50 19.e128

Histogram of Tests
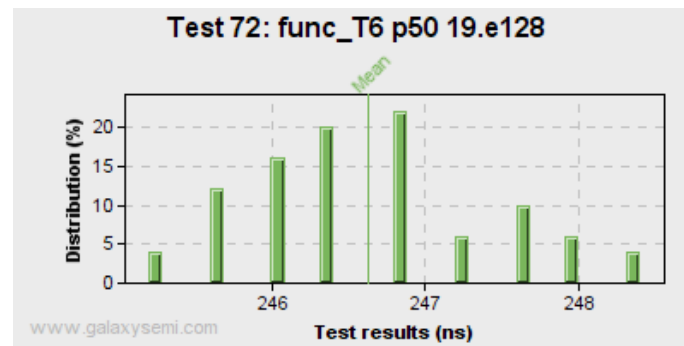
Test	73
Name	func_T6 A8 0
Test type	Parametric
Low limit	1 ns
High limit	100 ns
Exec / Fails	50 / 0 (0.00%)
Mean	15.624 ns
Sigma	1.11219 ns
Range	5.2 ns
Cp / Cpk	14.84 / 4.38
Samples	50
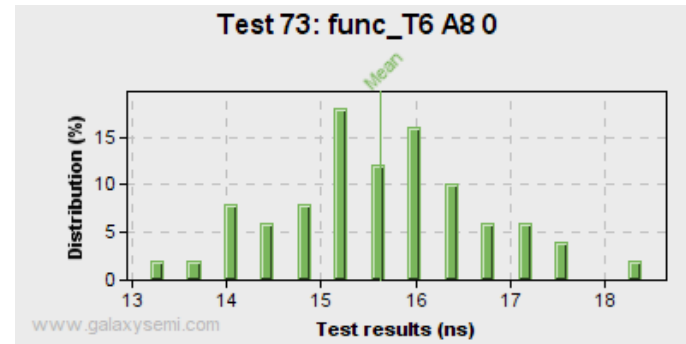
Test	75
Name	func_T7 p53 19.e135
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	3.28324 V
Sigma	0.00187966 V
Range	0.00900006 V
Cp / Cpk	n/a . / n/a .
Samples	50

Histogram of Tests
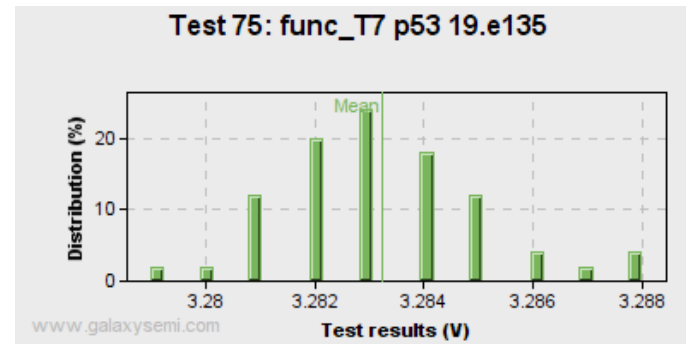
Test	76
Name	func_T7 p53 19.e135
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	0.13934
Sigma	0.00244624
Range	0.00999999
Cp / Cpk	n/a . / n/a .
Samples	50

Test 76: func_T7 p53 19.e135
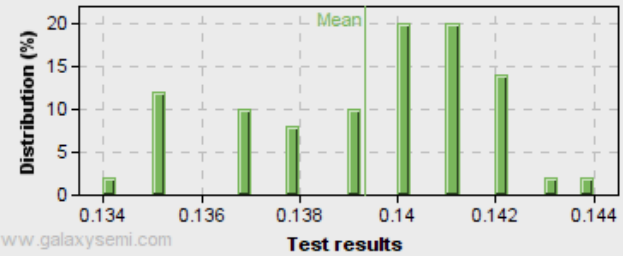
Test	81
Name	func_T8 A8 0
Test type	Parametric
Low limit	1 ns
High limit	20 ns
Exec / Fails	50 / 0 (0.00%)
Mean	9.336 ns
Sigma	1.26648 ns
Range	5.4 ns
Cp / Cpk	2.50 / 2.19
Samples	50

Test 81: func_T8 A8 0

Histogram of Tests
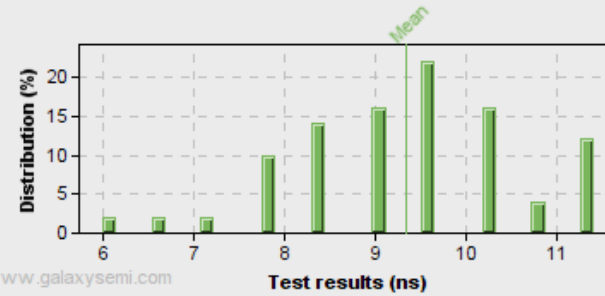
Test	786000
Name	Soft_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	50
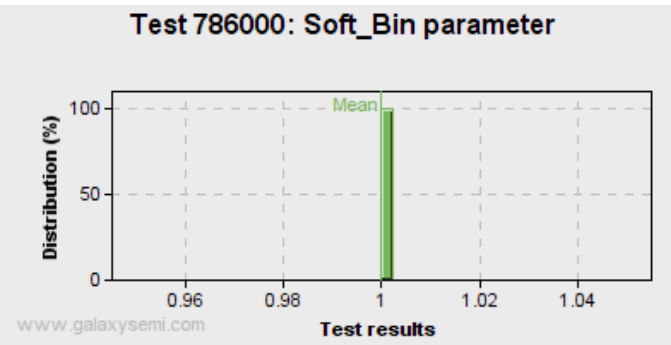
Test	786001
Name	Hard_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	50
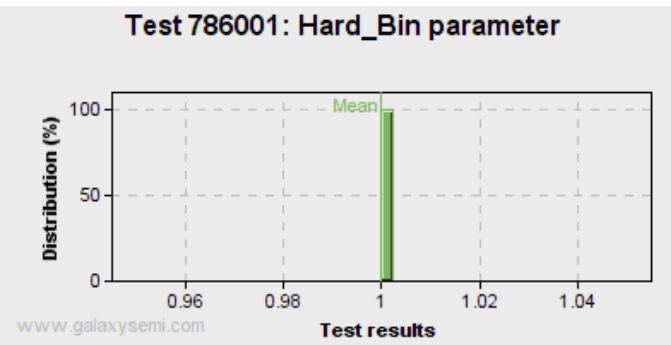
Test	786002
Name	Die_X parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	2.94
Sigma	2.0445
Range	6
Cp / Cpk	n/a . / n/a .
Samples	50

Test 786002: Die_X parameter
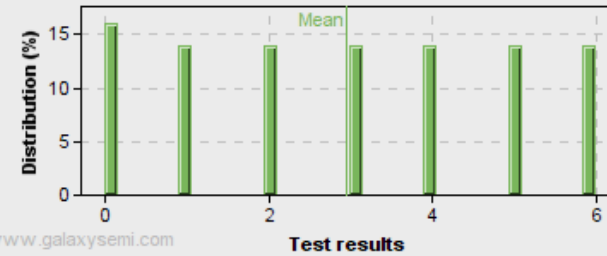
Test	786003
Name	Die_Y parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	3.92
Sigma	2.07846
Range	7
Cp / Cpk	n/a . / n/a .
Samples	50

Test 786003: Die_Y parameter

Histogram of Tests

Test	786004
Name	Test_Time parameter
Test type	–
Low limit	0.0 sec
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	2.89756 sec
Sigma	0.0315738 sec
Range	0.13 sec
Cp / Cpk	n/a . / 30.59
Samples	50

Test 786004: Test_Time parameter
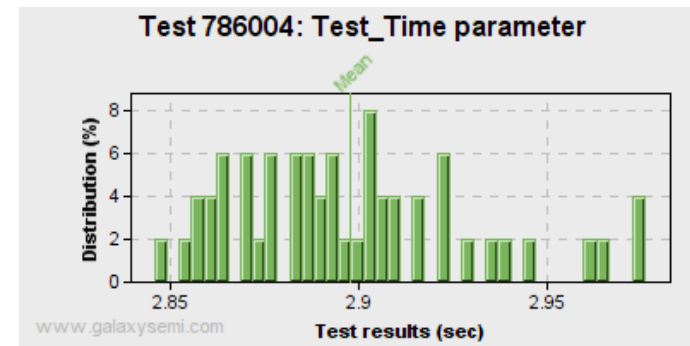
Test	786006
Name	Testing_Site parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	0
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	50

Test 786006: Testing_Site parameter

Histogram of Tests
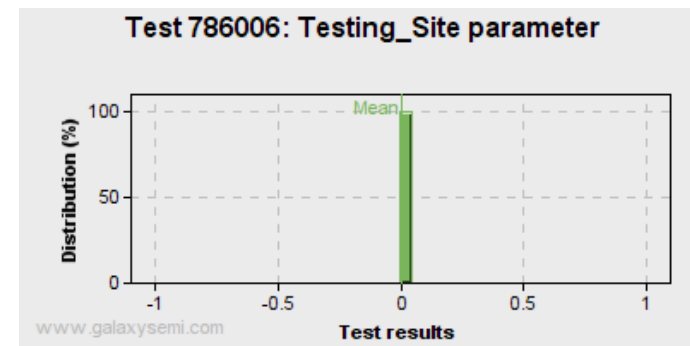
Test	786007
Name	Part_ID parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	29.5
Sigma	14.5774
Range	49
Cp / Cpk	n/a . / n/a .
Samples	50
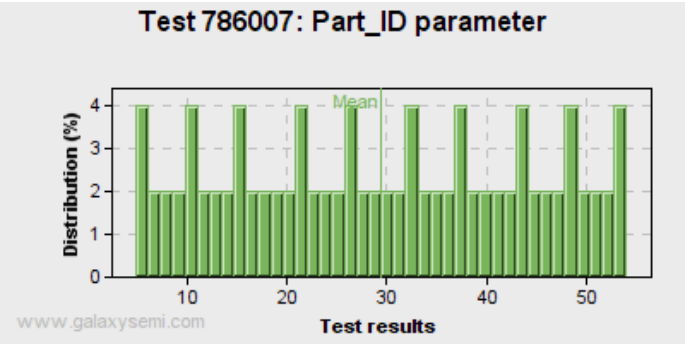
Pareto of Tests Cp

Test	Name	Cp	Test Cp Chart

Shows all Cp <= 1.7 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests Cpk

Test	Name	Cpk	Test Cpk Chart

Shows all Cpk <= 1.3 (Defined in <u>Options</u> , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests failures

Test	Name	Failing Bin	Failures count	Yield Loss	Fail contribution	Test Fail rate	Failures Chart
–	**Cumul. of failures**	–	0	0.0 %	0.0 %	0.0 %	

–– Yield loss: number of failed test executions / number of parts

–– Fail contribution: number of failed test executions / number of parts failed

–– Test Fail rate: number of failed test executions / number of test executions

Pareto of Functional Failure Signatures (pins tested in parallel)

Total devices tested: **51**
Total patterns detected: **0**

Fail count	% of failures	% of tested	Functional Failure signatures (tested pins failing together)

Shows first 25 % of the failure signatures (Defined in Options, section 'Pareto/Define Failure Signatures cut−off limit')

No Functional failure signature detected

Possible root cause: The 'Options/Data processing/Multi−results...' option is set to 'merge' instead of 'no merge'

Pareto of Parametric Failure Signatures (tests failing concurrently)

No Parametric failure signature detected

Pareto of Software Bins

Software Binning	Bin Name	Count	Percentage	Software Binning Chart
1	–	51	100.0 %	
Cumul.	**Cumul.**	**51**	**100.0%**	

Pareto of Hardware Bins

Hardware Binning	Bin Name	Count	Percentage	Hardware Binning Chart
1	–	51	100.0 %	████████████████████████
Cumul.	**Cumul.**	**51**	**100.0%**	

Wafermaps & Strip Maps

Map type	Show Software bins
Devices tested (with retests)	51
Total physical parts tested	50 (only applies to Wafermaps)

List of Individual Maps

Top 10 Software Binning	1
Color	
Pass/Fail	P
Percentage	100.0%
Total count	51

Map style	STRIP map (parts tested are PACKAGED DEVICES!)
Total physical parts tested	50
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Strip started	Thu Sep 05 03:45:28 2024
Strip ended	Thu Sep 05 03:49:59 2024
Wafer tested in	4 minutes 31 seconds
Average device test time	5.314 sec.
Map dimensions	LowX=0, LowY=0, HighX=6, HighY=7

0

Die Y locations

Run 1, Run 2,...
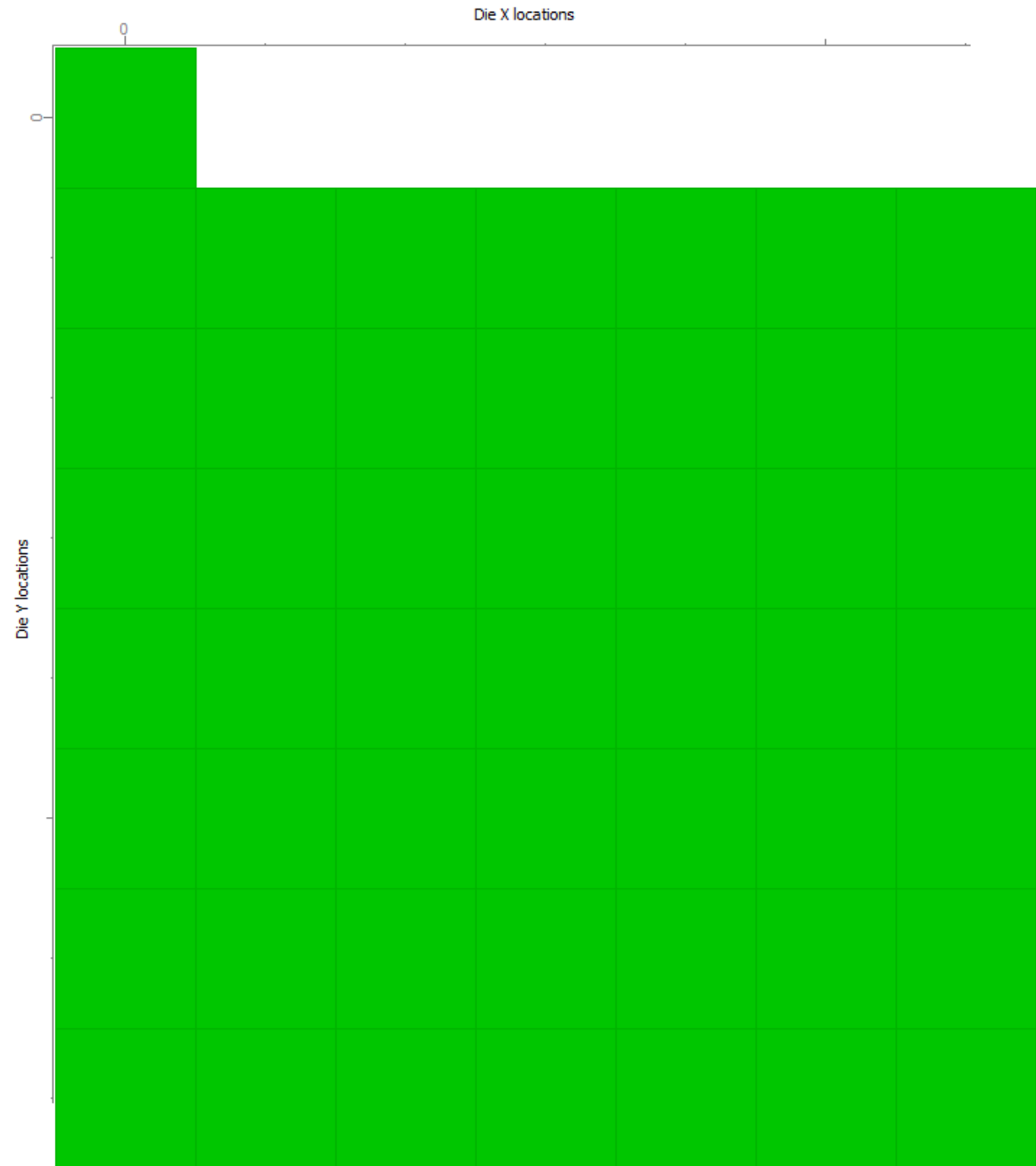
Software Binning Summary

Software Binning	Bin Name	Pass/ Fail	Total count	Percentage	Software Binning Chart
1	–	P	51	100.0 %	
All PASS Bins	**All PASS Bins**	P	**51**	**100.0 %**	
ALL Bins	**ALL Bins**	–	**51**	**100.0 %**	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Hardware Binning Summary

Hardware Binning	Bin Name	Pass/ Fail	Total count	Percentage	Hardware Binning Chart
1	–	P	51	100.0 %	■■■■■■■■■■■■■■■■■■
All PASS Bins	All PASS Bins	P	51	100.0 %	
ALL Bins	ALL Bins	–	51	100.0 %	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Message Log

No log message to report

Global Information

Report from	Teradyne–Examinator–Pro+ – V8.1.5 – www.galaxysemi.com
Report created	Wed Sep 04 15:52:07 2024
Data processed	298.0 KB (305198 bytes)
Processing time	0.79 second
Processing speed	384.9 KB/sec
Examinator expires	Sun Sep 3 2034
(null)	–
File name	C:/Users/rahmana/OneDrive – Teradyne/Desktop/New Hire/New Hire Tech/UFP New Hire Train/Project 1/i8243/results_notemp_50loops.std
Tests mapping file	n/a

Setup time	Thu Sep 05 03:45:28 2024
Start time	Thu Sep 05 03:45:28 2024
End time	Thu Sep 05 03:49:59 2024
Test duration	4 minutes 31 seconds
Product	n/a
Program	rahmana_i8243_p1.igxl
Revision	n/a
Lot	n/a
Sub−Lot	n/a
WaferID	n/a
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Test time (GOOD parts)	2.898 sec. (excludes tester idle time)
Test time (ALL parts)	2.898 sec. (excludes tester idle time)
Average test time	5.314 sec. / device (includes tester idle time between parts)
Total parts tested	51 − Includes parts retested (if any)
Good parts (Yield)	51 (100.00%) − Includes parts retested (if any)
Bad parts (Yield loss)	0 (0.00%) − Includes parts retested (if any)
Parts retested	n/a .
Parts aborted	0 (0.00%)
(null)	−
STDF Version	4.0
Tester name	SNG−UFP−789
Tester type	UltraFLEXplus
Station	1
Part type	n/a
Operator	rahmana
Exec_type	IG−XL
Exec_version	10.30.10_uflx (P1.11)
TestCode	n/a
Test Temperature	n/a
User Text	n/a
Aux_file	n/a
Package type	n/a
Per_freq	n/a
Spec_name	n/a
Spec_version	n/a
Family ID	n/a

Global Information

Date code	n/a
Design Rev	n/a
Facility ID	n/a
Floor ID	n/a
Proc ID	n/a
Flow ID	n/a
Setup ID	n/a
Eng ID	n/a
ROM code	n/a
Serial #	n/a
Super user name	n/a
Handler/Prober	n/a
(null)	–
Site details	Site# 0

Global Options

Test# policy	Never merge tests with identical test number if test name not matching
Data Cleaning	None (keep all data)
Statistics computation	From samples data (if any), otherwise from summary
Binning computation	From summary data (if any), otherwise from samples
Cp,Cpk computation	Use standard Sigma formula
Mean drift formula	Percentage of value drift